

ON Semiconductor®

FDC610PZ

P-Channel PowerTrench® MOSFET

-30V, -4.9A, 42mΩ

Features

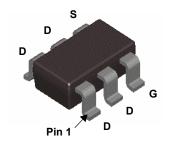
- Max $r_{DS(on)}$ = 42m Ω at V_{GS} = -10V, I_D = -4.9A
- Max $r_{DS(on)}$ = 75m Ω at V_{GS} = -4.5V, I_D = -3.7A
- Low gate charge (17nC typical).
- High performance trench technology for extremely low r_{DS(on)}.
- SuperSOTTM –6 package: small footprint (72% smaller than standard SO–8) low profile (1mm thick).
- RoHS Compliant

General Description

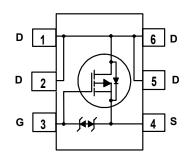
This P-Channel MOSFET is produced using ON Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance. These devices are well suited for battery power applications: load switching and power management, battery charging circuits, and DC/DC conversion.

Application

■ DC - DC Conversion



SuperSOTTM -6



MOSFET Maximum Ratings TA = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DS}	Drain to Source Voltage		-30	V	
V _{GS}	Gate to Source Voltage		±25	V	
I _D	Drain Current -Continuous	(Note 1a)	-4.9	^	
	-Pulsed		-20	Α	
D	Power Dissipation	(Note 1a)	1.6	10/	
P_{D}	Power Dissipation	(Note 1b)	0.8	W	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	78	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	156	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
.610Z	FDC610PZ	SSOT6	7"	8mm	3000units

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C		-22		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24V, V_{GS} = 0V$			-1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±10	μΑ

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1	-2.2	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = –250μA, referenced to 25°C		6		mV/°C
		$V_{GS} = -10V, I_D = -4.9A$		36	42	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -4.5V$, $I_D = -3.7A$		58	75	mΩ
		$V_{GS} = -10V$, $I_D = -4.9A$, $T_J = 125$ °C		50	60	
g _{FS}	Forward Transconductance	$V_{DD} = -10V, I_D = -4.9A$		15		S

Dynamic Characteristics

C _{iss}	Input Capacitance	\\ - 45\\ \\ - 0\\	755	1005	pF
C _{oss}	Output Capacitance	V _{DS} = -15V, V _{GS} = 0V, f = 1MHz	145	195	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1WITZ	125	190	pF
R_g	Gate Resistance	f = 1MHz	13		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		7	14	ns
t _r	Rise Time	$V_{DD} = -15V, I_{D} = -4.9A$ $V_{GS} = -10V, R_{GEN} = 6\Omega$	4	10	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = -10V, R _{GEN} - 012	33	53	ns
t _f	Fall Time		23	37	ns
Q_g	Total Gate Charge	V _{GS} = 0V to -10V	17	24	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } -4.5V V_{DD} = -15V,$	9	13	nC
Q _{gs}	Gate to Source Gate Charge	I _D = -4.9A	2.9		nC
Q_{gd}	Gate to Drain "Miller" Charge		4.3		nC

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain-Source Diode Forward Current			-1.3	Α
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = -1.3A$ (Note 2)	-0.8	-1.2	V
t _{rr}	Reverse Recovery Time	$I_F = -4.9A$, di/dt = 100A/ μ s	19	35	ns
Q _{rr}	Reverse Recovery Charge		9	18	nC

^{1.} R_{0,1A} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,1C} is guaranteed by design while R_{0,1C} is determined by the user's board design.



a. 78°C/W when mounted on a 1 in² pad of 2 oz copper.



b. 156°C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300μ s, Duty cycle < 2.0%.

Typical Characteristics T_J = 25°C unless otherwise noted

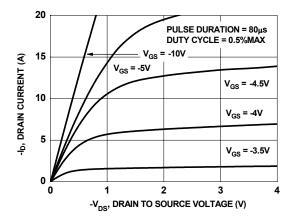


Figure 1. On-Region Characteristics

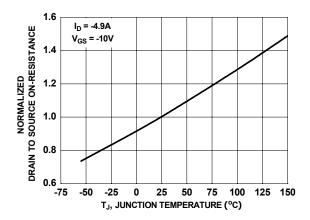


Figure 3. Normalized On-Resistance vs Junction Temperature

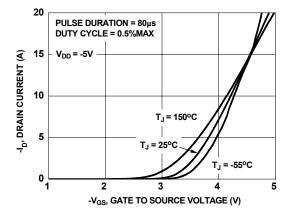


Figure 5. Transfer Characteristics

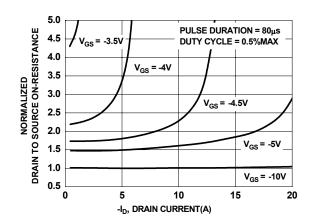


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

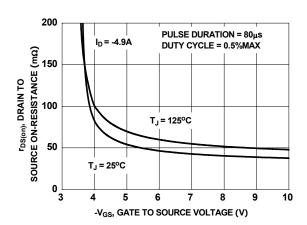


Figure 4. On-Resistance vs Gate to Source Voltage

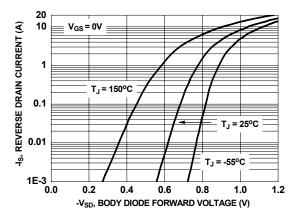


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

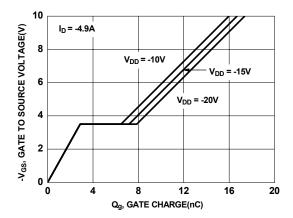
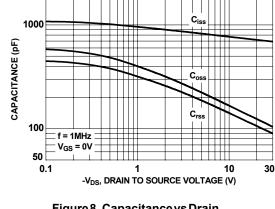


Figure 7. Gate Charge Characteristics



2000

Figure 8. Capacitance vs Drain to Source Voltage

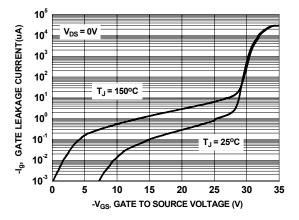


Figure 9. Gate Leakage Current vs Gate to Source Voltage

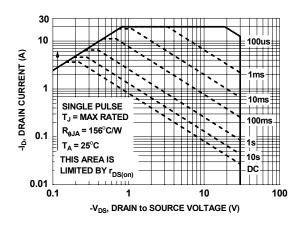


Figure 10. Forward Bias Safe Operating Area

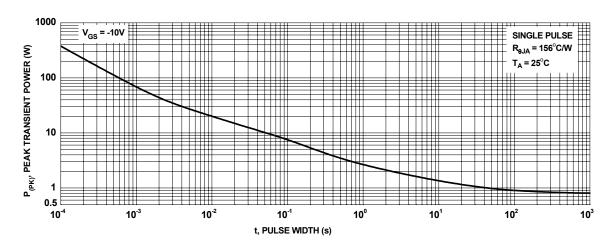


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

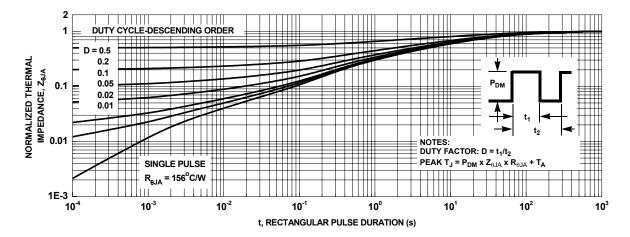


Figure 12. Transient Thermal Response Curve

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